# Application/Control No. O9/939,824 Examiner Joseph Waks Applicant(s)/Patent Under Reexamination FUKUDA ET AL. Art Unit Page 1 of 1

# Notice of References Cited

### **U.S. PATENT DOCUMENTS**

	1	Document Number	Date		T
*		Country Code-Number-Kind Code	MM-YYYY	Name	Classification
	Α	US-5,027,025	06-1991	Saneshige et al.	310/156.38
	В	US-			
	С	US-			
	D	US-			
	Е	US-			
	F	US-			
	G	US-			
	Н	US-			
	ŀ	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 1010433 A	04-1998	Japan	Toshiba-Lightech	
	0	JP 05103451 A	04-1993	Japan		H02K 05/22
	Р	JP 0970162 A	03-1997	Japan	Matsushita Denki	
	Q	JP 10295068 A	11-1998	Japan	Sankyo Seiki	H02K 05/22
	R	WO 01/43261 A1	06-2001	WIPO	Yoshida et al.	
	S					
	Т					

### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U					
	V					
	w					
	х					

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.